



Integrated Device Technology, Inc.
2975 Stender Way, Santa Clara, CA - 95054

PRODUCT/PROCESS CHANGE NOTICE (PCN)

PCN #: **I0107-04** DATE: 9/17/01
 Product Affected: IDT79RC64T574/ 79RC64T575
 Manufacturing Location Affected: All
 Date Effective: 9/17/01

MEANS OF DISTINGUISHING CHANGED DEVICES:
 Product Mark
 Back Mark
 Date Code N/A
 Other

Contact: Bimla Paul
 Title: Product Assurance Manager Attachment:: Yes No
 Phone #: 408-654-6419
 Fax #: 408-492-8362 Samples: N/A
 E-mail: bimla.paul@idt.com

DESCRIPTION AND PURPOSE OF CHANGE:

- Die Technology
- Wafer Fabrication Process
- Assembly Process
- Equipment
- Material
- Testing Data Sheet Changes. Refer to attachment for details.
- Manufacturing Site The latest data sheet dated April, 2001 can be viewed at IDT web site:
- Data Sheet http://www.idt.com/products/pages/Communications_Processors-PL100_Sub205_Dev395.html
- Other

RELIABILITY/QUALIFICATION SUMMARY:

N/A

CUSTOMER ACKNOWLEDGMENT OF RECEIPT:

IDT records indicate that you require written notification of this change. Please use the acknowledgement below or E-Mail to grant approval or request additional information. If IDT does not receive acknowledgement within 30 days of this notice it will be assumed that this change is acceptable.
 IDT reserves the right to ship either version manufactured after the process change effective date until the inventory on the earlier version has been depleted.

Customer: _____ **Approval for shipments prior to effective date.**
 Name/Date: _____ E-Mail Address: _____
 Title: _____ Phone# /Fax# : _____

CUSTOMER COMMENTS: _____

IDT ACKNOWLEDGMENT OF RECEIPT:

RECD. BY: _____ DATE: _____



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ATTACHMENT - PCN #: I0107-04

PCN Type: Data Sheet Change

Detail of Change Selective data sheet limits have been revised as follows:

Items	Old Revision	New Revision
System Interface Parameters Data Output Hold-TDOH (Min)	1.0 ns (mode =all)	0 ns (mode = all)
DC Electrical Characteristics Iin (Max) I/O Leak (Max)	+/- 10 μ A 20 μ A	+/- 50 μ A 50 μ A
Power Consumption Icc standby (Max)	120 mA	200 mA
Output Loading for AC testing (page 21)	Vref diagram All signals = 50 pF	Lump capacitance All signals = 25 pF